## **AMENDMENTS TO THE CLAIMS**

- 1. (Canceled).
- 2. (Withdrawn) The resistance-changing function body as claimed in Claim 1, wherein the object made of the first substance is an insulator, and the particles made of the second substance are electrically conductive particles.
- 3. (Withdrawn) The resistance-changing function body as claimed in Claim 2, wherein the conductive particles include those having particle sizes not less than 0.2 nm and less than 4nm.
- 4. (Withdrawn) A memory having the resistance-changing function body as defined in Claim 1, wherein
- a rectifying function body having a rectification effect is electrically connected in series with the resistance-changing function body so as to determine a direction of a current that flows through the resistance-changing function body.
- 5. (Withdrawn) A memory having the resistance-changing function body as defined in Claim 1, wherein
- a select transistor for selecting the resistance-changing function body is electrically connected in series with the resistance-changing function body.

6. (Withdrawn) A memory comprising at least two memory cells including the resistancechanging function body as defined in Claim 1, wherein

the objects made of the first substance in the two memory cells are integrally continuously formed, and

of the two memory cells, one electrode of one memory cell and one electrode of the other memory cell are electrically connected to each other, and the other electrode of the one memory cell and the other electrode of the other memory cell are electrically isolated from each other.

7. (Withdrawn) A memory comprising at least five memory cells including the resistance-changing function body as defined in Claim 1, a select transistor for selecting the resistance-changing function body and a rectifying function body for determining a direction of a current that flows through the resistance-changing function body, wherein

each of the memory cells is connected between a bit line and a source line extended in a direction of column, and the select transistor of each of the memory cells is controlled by a word line extended in a direction of row,

second and fourth cells are arranged mutually adjacently in the direction of row, and third and fifth cells are arranged mutually adjacently in the direction of column, with respect to a first cell of the five memory cells,

the first cell and the second cell have a shared bit line, a shared word line and unshared source lines,

the first cell and the third cell have a shared bit line, a shared source line and unshared word lines,

the first cell and the fourth cell have a shared source line, a shared word line and unshared bit lines, and

the first cell and the fifth cell have a shared word line, a source line of the first cell and a bit line of the fifth cell are shared, and a bit line of the first cell and a source line of the fifth cell are shared.

## 8. (Currently Amended) A memory in which:

at least two memory cells including the <u>a</u> resistance-changing function body <del>as defined in</del> Claim 1 are arranged in a direction common plane parallel to a substrate; <del>and</del>

the resistance-changing function body of each of the memory cells comprises:

an object made of a first substance and interposed between a first electrode and a second electrode; and

a plurality of particles made of a second substance and arranged within the object so that an electrical resistance between the first electrode and the second electrode is changed before and after application of a specified voltage between the first electrode and the second electrode, wherein

the first substance makes an electrical barrier against the second substance, and
the objects made of the first substance of memory cells mutually adjacent in the direction
parallel to the substrate are integrally continuously formed.

## 9. (Withdrawn) A memory in which:

at least two memory cells including the resistance-changing function body as defined in

Claim 1 and a rectifying function body for determining a direction of a current that flows through

the resistance-changing function body are arranged in a direction parallel to a substrate, and

the objects made of the first substance and/or the rectifying function bodies of memory

cells mutually adjacent in the direction parallel to the substrate are integrally continuously

formed.

10. (Withdrawn) The resistance-changing function body as claimed in Claim 1, wherein

a third electrode which allows a voltage to be applied to the object made of the first

substance in a direction substantially perpendicular to a direction in which the first electrode and

the second electrode are opposed to each other is adjacent to the object made of the first

substance.

11. (Withdrawn) The resistance-changing function body as claimed in Claim 1, wherein

its electrical characteristics vary depending on whether the voltage applied to the third

electrode is positive or negative.

12. (Withdrawn) The resistance-changing function body as claimed in Claim 1, wherein

the plurality of particles include at least two kinds of particles, which are a relatively

small particle and a relatively large particle.

13. (Withdrawn) The resistance-changing function body as claimed in Claim 10, wherein

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the particles are distributed uniformly with respect to a layer direction substantially

parallel to the direction in which the first electrode and the second electrode are interconnected,

and moreover the particles are distributed within a certain range with respect to a thickness

direction perpendicular to the layer direction.

14. (Withdrawn) The resistance-changing function body as claimed in Claim 13, wherein

concentration of an element constituting the particles is maximized in one position within

the distribution and reduced away from the position in the thickness directions.

15. (Withdrawn) The resistance-changing function body as claimed in Claim 13, wherein

density of the particles is maximized in one position within the distribution and reduced

away from the position in the thickness directions.

16. (Withdrawn) The resistance-changing function body as claimed in Claim 13, wherein

particle size of the particles is maximized in one position within the distribution and

reduced away from the position in the thickness directions.

17. (Withdrawn) The resistance-changing function body as claimed in Claim 13, wherein

the particles include at least two kinds of particles, which are a relatively small particle

and a relatively large particle, and

an angle at which a straight line interconnecting the two particles intersects with a plane

extending along the layer direction is not less than 45 degrees.

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- 18. (Withdrawn) The resistance-changing function body as claimed in Claim 16, wherein the distribution of particle sizes of the particles is asymmetrical between both sides of the position at which the particle size is maximized with respect to the thickness direction.
- 19. (Withdrawn) The resistance-changing function body as claimed in Claim 13, wherein the object made of the first substance is an insulator, and

film thickness of the insulator in the thickness direction is not less than 2 nm and less than 50 nm.

20. (Withdrawn) A memory having the resistance-changing function body as defined in Claim 10, wherein

the first electrode and the second electrode are diffusion regions, respectively, formed on a surface of a semiconductor substrate,

the object made of the first substance is formed in a region located between the diffusion regions within the surface of the semiconductor substrate, and

the third electrode is provided on the object made of the first substance.

21. (Withdrawn) A memory having the resistance-changing function body as defined in Claim 10, wherein

the first electrode and the second electrode are conductors, respectively, formed on a substrate,

the object made of the first substance is formed in a region interposed between the conductors, and

the third electrode is provided on the insulator.

22. (Withdrawn) The resistance-changing function body as claimed in Claim 10, wherein a fourth electrode is provided at a position confronting the third electrode with the object made of the first substance interposed therebetween,

the plurality of particles are so arranged that an electrical resistance between the first electrode and the second electrode is changed before and after application of a specified voltage to between the third electrode and the fourth electrode.

- 23. (Withdrawn) A memory in which at least two resistance-changing function bodies as defined in Claim 22 are stacked in a direction perpendicular to the substrate.
- 24. (Withdrawn) A method for manufacturing the resistance-changing function body as defined in Claim 2, comprising a step of implanting the second substance for forming the particles into the object made of the first substance by a negative ion implantation method.
- 25. (Withdrawn) The method for manufacturing the resistance-changing function body as claimed in Claim 24, comprising a step of carrying out hydrogen sintering after the negative ion implantation ends.
- 26. (Withdrawn) The method for manufacturing the resistance-changing function body claimed in Claim 24, comprising a step of carrying out heat treatment at a temperature of not lower than 500°C after the negative ion implantation ends.

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27. (Withdrawn) A memory having the resistance-changing function body as defined in

Claim 1.

28. (Withdrawn) A circuit having the memory as defined in Claim 26.

29. (Withdrawn) Electronic equipment having the circuit as defined in Claim 27.

30. (Withdrawn) A resistance-changing function body comprising:

a medium made of a first material and formed between a first conductor and a second

conductor; and

at least one conductive particle which is formed within the medium and which is covered

with a second material and made of a third material, wherein

the second material is a material serving as a barrier against passage of electric charges

therethrough, and

the third material is a material having a function of retaining electric charges.

31. (Withdrawn) The resistance-changing function body as claimed in Claim 30, wherein

the second material is obtained by compositionally changing or chemically modifying the

third material.

32. (Withdrawn) The resistance-changing function body as claimed in Claim 30, wherein

the second material is obtained by oxidizing or nitriding the third material.

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The memory as defined in Claim 8, wherein 33. (New)

each of the memory cells includes a rectifying function body for determining a direction

of a current that flows through the resistance-changing function body.

The memory as defined in Claim 8, wherein 34. (New)

each of the memory cells includes a rectifying function body for determining a direction

of a current that flows through the resistance-changing function body, and

the objects made of the first substance and the rectifying function bodies of memory cells

mutually adjacent in the direction parallel to the substrate are integrally continuously formed.

The memory as defined in Claim 8, wherein 35. (New)

in two memory cells of the at least two memory cells, one electrode of one memory cell

and one electrode of the other memory cell are electrically connected to each other, and the other

electrode of the one memory cell and the other electrode of the other memory cell are electrically

isolated from each other.

36. (New) The memory as defined in Claim 33, comprising at least five of the memory cells,

wherein

each of the memory cells includes a select transistor for selecting the resistance-changing

function body,

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each of the memory cells is connected between a bit line and a source line extended in a

direction of a column, and the select transistor of each of the memory cells is controlled by a

word line extended in a direction of a row,

second and fourth cells are arranged mutually adjacently in the direction of row, and third

and fifth cells are arranged mutually adjacently in the direction of the column, with respect to a

first cell of the five memory cells,

the first cell and the second cell have a shared bit line, a shared word line and unshared

source lines,

the first cell and the third cell have a shared bit line, a shared source line and unshared

word lines,

the first cell and the fourth cell have a shared source line, a shared word line and

unshared bit lines, and

the first cell and the fifth cell have a shared word line, a source line of the first cell and a

bit line of the fifth cell are shared, and a bit line of the first cell and a source line of the fifth cell

are shared.

37. (New) The memory as defined in Claim 8, wherein the plurality of particles in the

resistance-changing function body include at least two kinds of particles, which are a relatively

small particle and a relatively large particle.

38. (New) The memory as defined in Claim 37, wherein

an angle at which a straight line interconnecting the two particles intersects with a plane

extending along a layer direction parallel to the substrate is not less than 45 degrees.

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39. (New) The memory as defined in Claim 8, wherein

each of the particles includes, in addition to a center part which is made of the second

substance and has a function of retaining electric charges, a coating part which covers the center

part and is made of a material serving as a barrier against passage of electric charges through the

coating part.

40. (New) The memory as defined in Claim 39, wherein

the material of the coating part is obtained by compositionally changing or chemically

modifying the second substance of the center part.

41. (New) The memory as defined in Claim 39, wherein the material of the coating part is

obtained by oxidizing or nitriding the second substance of the center part.

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